MSKSEMI















ESD

TVS

TSS

MOV

GDT

PLED

Brodnet data speet

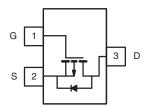
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SOT-23



General Features

$$\begin{split} &V_{DS}\text{ =-60V,I }_{D}\text{ =-2A} \\ &R_{DS(ON)}\text{ <160m}\Omega\text{ @ }V_{GS}\text{=-10V} \\ &R_{DS(ON)}\text{ <200m}\Omega\text{ @ }V_{GS}\text{=-4.5V} \end{split}$$

Application

Load switch
PWM application

Absolute Maximum Ratings (TA=25[°]C unless otherwise noted)

Symbol	Parameter	Limit	Unit
VDS	Drain-Source Voltage	-60	V
V _G s	Gate-Source Voltage	±20	V
l _D	Drain Current-Continuous	-2	А
Ідм	Drain Current-Pulsed (Note 1)	-8	А
P _D	Maximum Power Dissipation	1.5	W
T _J ,T _{STG}	Operating Junction and Storage Temperature Range	-55 To 150	$^{\circ}$
Reja	Thermal Resistance,Junction-to-Ambient (Note 2)	83.3	°C/W

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Electrical Characteristics (T_C=25 °C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS} V _{GS} =0V I _D =-250μA		-60	-	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-60V,V _{GS} =0V	-	-	-1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±20V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} ,I _D =-250μA	-1.4	-2.0	-2.6	٧
Drain-Source On-State Resistance	В	V _{GS} =-10V, I _D =-1.5A	-	140	160	mΩ
Dialii-Source Oii-State Resistance	R _{DS(ON)}	V _{GS} =-4.5V, I _D =-1.5A	-	160	200	mΩ
Forward Transconductance	g FS	V _{DS} =-5V,I _D =-1.5A		3	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C_{lss}	\/ - 20\/\/ -0\/	-	444.2	-	PF
Output Capacitance	Coss	V_{DS} =-30V, V_{GS} =0V, F=1.0MHz	-	19.6	-	PF
Reverse Transfer Capacitance	C _{rss}	F=1.UIVID2	-	17.9	-	PF
Switching Characteristics (Note 4)			•			
Turn-on Delay Time	t _{d(on)}		-	40	-	nS
Turn-on Rise Time	t _r	V_{DD} =-30V, I_{D} =-1.5A,	-	35	-	nS
Turn-Off Delay Time	$t_{\sf d(off)}$	V_{GS} =-10 V , R_{G} =3 Ω	-	15	-	nS
Turn-Off Fall Time	t _f		-	10	-	nS
Total Gate Charge	Q_g	V - 20 I - 4 FA	-	11.3	-	nC
Gate-Source Charge	Q _{gs}	V_{DS} =-30, I_{D} =-1.5A, V_{GS} =-10V	-	2.7	-	nC
Gate-Drain Charge	Q_{gd}	VGS=-10V	-	1.6	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =-1.5A	-		-1.2	V
Diode Forward Current (Note 2)	Is		-	-	-1.6	Α
Reverse Recovery Time	t _{rr}	T _J = 25°C, I _F =- 1.5A	-	25		nS
Reverse Recovery Charge	Qrr	$di/dt = -100A/\mu s^{(Note3)}$	-	31		nC

Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- **3.** Pulse Test: Pulse Width ≤ 300μ s, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production

Typical Electrical and Thermal Characteristics (Curves)

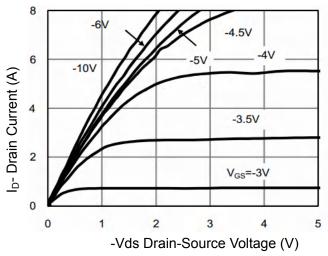


Figure 1 Output Characteristics

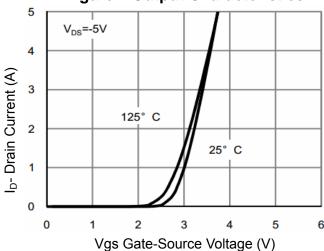
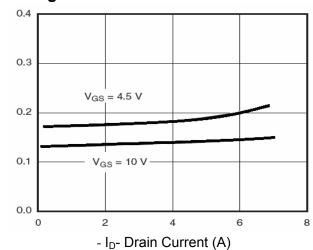


Figure 2 Transfer Characteristics



Rdson On-Resistance(()

Figure 3 Rdson- Drain Current

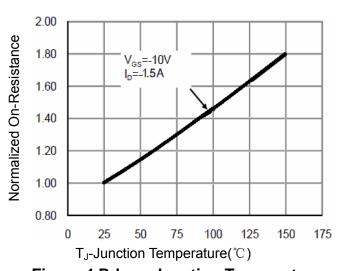


Figure 4 Rdson-Junction Temperature

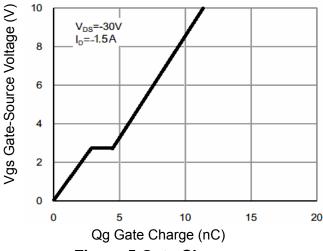


Figure 5 Gate Charge

1.0E+01

1.0E+00

1.0E-01

1.0E-02

1.0E-03

1.0E-03

1.0E-04

--
1.0E-05

0.0

0.2

0.4

0.6

0.8

1.0

-Vsd Source-Drain Voltage (V)

Figure 6 Source- Drain Diode Forward



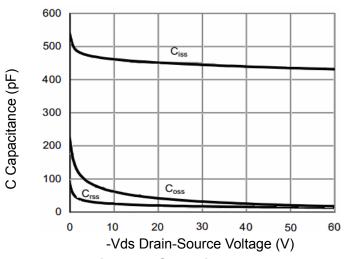


Figure 7 Capacitance vs Vds

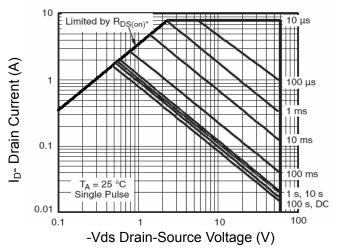


Figure 8 Safe Operation Area

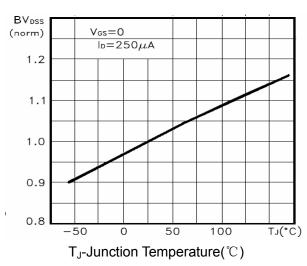


Figure 9 BV_{DSS} vs Junction Temperature

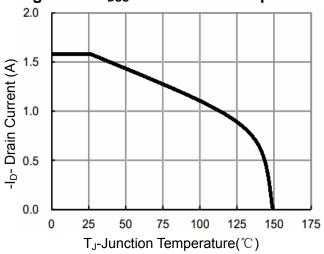
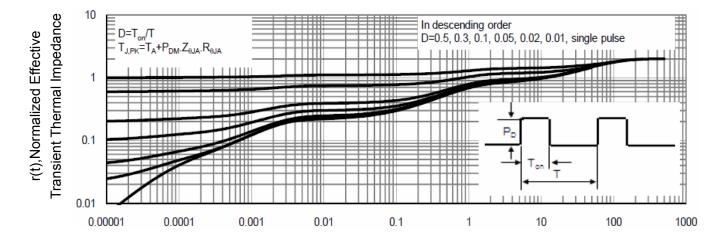


Figure 10 ID Current De-rating



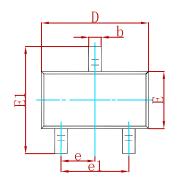
Square Wave Pluse Duration(sec)

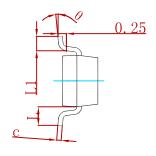
Figure 11 Normalized Maximum Transient Thermal Impedance

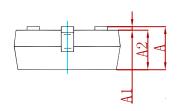




PACKAGE MECHANICAL DATA

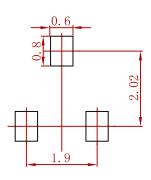






Cumbal	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950) TYP	0.037	7 TYP	
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

Suggested Pad Layout



- 1.Controlling dimension:in millimeters.2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
SI2309CDS-T1-MS	SOT-23	3000



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